Search Notes

_	Application/Control No.	Applicant(s)/Patent under Reexamination	
	09/467,611	MIAO ET AL.	
	Examiner	Art Unit	
	Jason M. Perilla	2611	

	SEARCHED				
Class	Subclass	Date	Examiner		
375	295	5/15/2007	JP		
	316	5/15/2007	JP		
	346	5/15/2007	JP		
	147	5/15/2007	JP		
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INTERFERENCE SEARCHED					
Çlass	Subclass	Date	Examiner		
375	147	5/15/2007	JP		
	316	5/15/2007	JP		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East USPAT/USPGPUB	5/15/2007	JP
Inventor Name Search EAST/EDAN	5/15/2007	JP
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